

**Reticle/Mask Foreign Matter Inspection** 

## PD Xpadion

## Features

- Works with various HORIBA sensors (Raman Spectroscopy, ellipsometry ect.)
- Adding reduction of detection errors
- New reprocessing features
- A new review function makes it possible to reduce the engineering time on particle control
- Innovative new software improves usability
- OHT, EFEM, multi-port, multi-slot support

